

Status:	CLOSED	Start date:	2022-08-23
Priority:	High	Due date:	
Assignee:	SZ HW Test-曾小文	% Done:	0%
Category:	EE	Estimated time:	0.00 hour
Target version:			
Need_Info:	--	Found Version:	2022.08.19
Resolution:	--	Degrated:	--
Severity:	Major	Verified Version:	
Reproducibility:	Every time	Fixed Version:	
Test Type:	Release Test	Root cause:	
Description			
From To Test Point SPEC Test Result			
Min Typ Max Units Measured Value Pass / Fail Notes			
VDVDD	VIN	C12253 to TP10452	0 - - ms -0.9338 Fail
VIODVDD	VIN	C12255 to TP10452	0 - - ms -0.93378 Fail
VIN	VIN	TP10452	25 - - ms 0 Fail

History

#1 - 2022-08-26 10:22 - SZ-硬件二组_SD3 王苗

这个电源不是外部供电，电源为芯片本身产生的。测试case与设计不符合

#2 - 2022-08-26 10:36 - SZ-硬件二组_SD3 王苗

- Assignee changed from SZ-硬件二组_SD3 王苗 to SZ HW Test-曾小文

VDVDD VIODVDD 电源不是外部供电，电源为芯片本身产生的。芯片只有一个VIN供电。测试case与设计不符合。

#3 - 2022-09-05 10:52 - 项目二组_SD3 曾小文

- Status changed from New to RESOLVED

8/23:VDVDD/VIODVDD为内部供电，研发评估不关注时序

#4 - 2022-09-05 11:45 - 项目二组_SD3 曾小文

- Status changed from RESOLVED to VERIFIED

#5 - 2022-09-05 11:46 - 项目二组_SD3 曾小文

- Status changed from VERIFIED to CLOSED

#6 - 2022-09-14 11:55 - CD TPM-申艳艳

- Category set to EE

Files

violdvdd-ch1,vin-ch2.png	50.9 KB	2022-08-23	SZ HW Test-曾小文
vdvdd-ch1,vin-ch2.png	52.7 KB	2022-08-23	SZ HW Test-曾小文